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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/620,284	07/14/2003	Robert C. Pack	CA7010502001	7731
23639	7590	02/24/2006	EXAMINER	
BINGHAM, MCCUTCHEN LLP THREE EMBARCADERO CENTER 18 FLOOR SAN FRANCISCO, CA 94111-4067			TAT, BINH C	
			ART UNIT	PAPER NUMBER
			2825	

DATE MAILED: 02/24/2006

Please find below and/or attached an Office communication concerning this application or proceeding.

# Office Action Summary

Application No.

10/620,284

Applicant(s)

PACK ET AL.

Examiner

Binh C. Tat

Art Unit

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-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --

## Period for Reply

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) OR THIRTY (30) DAYS, WHICHEVER IS LONGER, FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

## Status

- 1) ☒ Responsive to communication(s) filed on 02 December 2005.
- 2a) ☐ This action is **FINAL**. 2b) ☒ This action is non-final.
- 3) ☐ Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

## Disposition of Claims

- 4) ☒ Claim(s) 1-14, 23-36 and 45-53 is/are pending in the application.
- 4a) Of the above claim(s) 6-14, 28-36, 46, 49 and 52 is/are withdrawn from consideration.
- 5) ☐ Claim(s) \_\_\_\_\_ is/are allowed.
- 6) ☒ Claim(s) 1-5, 23-27, 45, 47, 48, 50, 51 and 53 is/are rejected.
- 7) ☐ Claim(s) \_\_\_\_\_ is/are objected to.
- 8) ☐ Claim(s) \_\_\_\_\_ are subject to restriction and/or election requirement.

## Application Papers

- 9) ☐ The specification is objected to by the Examiner.
- 10) ☒ The drawing(s) filed on 14 July 2003 is/are: a) ☒ accepted or b) ☐ objected to by the Examiner.  
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).  
Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).
- 11) ☐ The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.

## Priority under 35 U.S.C. § 119

- 12) ☐ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
- a) ☐ All b) ☐ Some \* c) ☐ None of:
- ☐ Certified copies of the priority documents have been received.
  - ☐ Certified copies of the priority documents have been received in Application No. \_\_\_\_\_.
  - ☐ Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).
- \* See the attached detailed Office action for a list of the certified copies not received.

## Attachment(s)

- ☒ Notice of References Cited (PTO-892)
- ☐ Notice of Draftsperson's Patent Drawing Review (PTO-948)
- ☒ Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08)  
Paper No(s)/Mail Date 07/24/05, 12/01/05.
- ☐ Interview Summary (PTO-413)  
Paper No(s)/Mail Date. \_\_\_\_\_.
- ☐ Notice of Informal Patent Application (PTO-152)
- ☐ Other: \_\_\_\_\_.

### DETAILED ACTION

1. This office action is in response to application 10/620284 filed on 06/24/03. The examiner acknowledges: the election of group I, claims 1-5, 23-27, 45, 47, 48, 50, 51, and 53 without traverse. The withdraw of non-election claims 6-14, 28-36, 46, 49, and 52.

#### *Claim Rejections - 35 USC § 102*

The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless –

(e) the invention was described in (1) an application for patent, published under section 122(b), by another filed in the United States before the invention by the applicant for patent or (2) a patent granted on an application for patent by another filed in the United States before the invention by the applicant for patent, except that an international application filed under the treaty defined in section 351(a) shall have the effects for purposes of this subsection of an application filed in the United States only if the international application designated the United States and was published under Article 21(2) of such treaty in the English language.

1. Claims 1-5, 23-27, 45, 47, 48, 50, 51, and 53 are rejected under 35 U.S.C. 102(e) as being anticipated by Pang et al. (U.S Patent 6578188).
2. As to claims 1, and 27 Pang et al. teach a method for writing a mask, comprising: generating integrated circuit design data (see fig 3, fig 7, col 2 lines 57 to col 4 lines 68); and using information for interfeature relationships of the integrated circuit design data to inspect the mask (see fig 3 fig 7, fig 8 col 2 lines 58 to col 3 line 37 and col 16 line 47 to col 18 lines 34).
3. As to claim 2, and 24 Pang et al. teach wherein the interfeature relationships are on one layer of the integrated circuit design (see col 1 line 43 to col 2 line 57).
4. As to claim 3, and 25 Pang et al. teach wherein the interfeature relationships am across multiple layers of the integrated circuit design (see fig 1-3 col 2 line 18 to col 4 line 63).
5. As to claim 4, and 26 Pang et al. teach wherein the interfeature relationships comprise: interfeature process proximity effects (see fig 3 fig 7, fig 8 col 2 lines 58 to col 3 line 37 and col

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16 line 47 to col 18 lines 34); interfeature coupling across layers (see fig 3 fig 7, fig 8 col 2 lines 58 to col 3 line 37 and col 16 line 47 to col 18 lines 34); interfeature electronic relationships; or wire interconnects longer than a given length (see fig 3 fig 7, fig 8 col 2 lines 58 to col 3 line 37 and col 16 line 47 to col 18 lines 34).

6. As to claim 5, and 27 Pang et al. teach wherein the information for interfeature relationships includes information for identifying a redundancy of features, and using the information for interfeature relationships to inspect the mask further comprises: determining that at least one feature is functional; and waiving one or more defects on features redundant to the functional feature (see fig 3 fig 7, fig 8 col 2 lines 58 to col 3 line 37 and col 16 line 47 to col 18 lines 34).

7. As to claim 45, and 47 Pang et al. teach wherein using information for interfeature relationships comprises using information for interfeature relationships to inspect the mask by inspecting elements of the mask in an order based on the interfeature relationships (see fig 3 fig 7, fig 8 col 2 lines 58 to col 3 line 37 and col 16 line 47 to col 18 lines 34 and background).

8. As to claim 48, and 50 Pang et al. teach wherein using information for interfeature relationships comprises using information for interfeature relationships to inspect the mask by adjusting the power of an inspection beam according to the interfeature relationships (see fig 3 fig 7, fig 8 col 2 lines 58 to col 3 line 37 and col 16 line 47 to col 18 lines 34 and background and summary).

9. As to claim 51, and 53 Pang et al. teach wherein portions of the mask are assigned different priorities according to the interfeature relationships (see fig 3 fig 7, fig 8 col 2 lines 58 to col 3 line 37 and col 16 line 47 to col 18 lines 34).

***Conclusion***

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Binh C. Tat whose telephone number is 571 272-1908. The examiner can normally be reached on 7:30 - 4:00 (M-F).

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Jack Chiang can be reached on 571 272 7483. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Binh Tat  
Art unit 2825  
February 20, 2006

*Murando*  
THUAN DO  
Primary examiner.  
02/21/06.